



■ EZ TEMPerature : AFM Temperature control

The Nano-Observer AFM is compatible with the temperature control accessory EZ temperature and peltier developed by CSI to deliver precise temperature control and imaging during temperature changes. It is compatible with all AFM modes. A heating or cooling sample stage is available to study temperature-dependent surface phenomena like phase transitions on polymers, materials or biological samples. Temperature range is from -40°C to 250°C . The design of the Nano-Observer architecture minimizes the temperature gradient between the heating/cooling stage and the scanner, so that thermal drift is minimized. This allows to perform stable imaging during temperature rise.

» Benefits

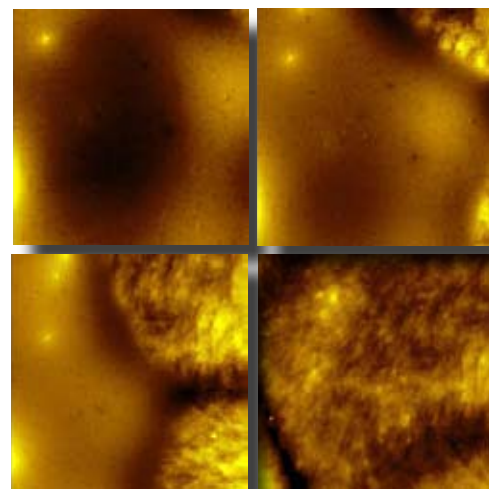
- Limited thermal expansion
- Working in low temperature
- Thermal insulation
- -40°C to 250°C
- Precise temperature
- Imaging during temperature change
- Stability and reproducibility

» Applications

- Polymers
- Biology
- Materials
- Electrical measurements...



» See video on the website



Real time acquisition, polymer crystallization under temperature control, $10\ \mu\text{m}$

» Specifications



EZ Temp stage
ambient to 250°C



Peltier stage
 -40°C to ambient

Temperature	-40°C to 250°C
Active zone	$\varnothing 25\text{mm}$
Sample size	$\varnothing 48\text{mm}$, $\varnothing 32.5\text{mm}$ in liquid
Height sample	max 4mm
Temperature precision	0.1°C
Compatible with	all AFM modes